# IRFP250NPbF



V <sub>(BR)DSS</sub>	200V
R <sub>DS(on)</sub> max.	0.075Ω
ID	30A

### Features

- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Ease of Paralleling
- Simple Drive Requirements
- Lead-Free

### Description

Fifth Generation HEXFET Power MOSFETs utilizes advanced processing techniques to achieve extremely low onresistance per silicon area. This benefit combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of other applications.

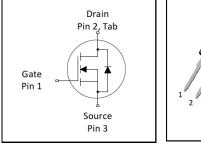
The TO-247AC package is preferred for commercial-industrial applications where higher power levels preclude th use of TO-220 devices. The TO-247AC is similar but superior to the earlier TO-218 package because of its isolated mounting hole.

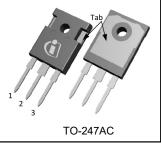
Base part number	Bookogo Typo	Standard Pack		Orderable Part Number
	Package Type	Form	Quantity	Orderable Part Nulliber
IRFP250NPbF	TO-247AC	Tube	25	IRFP250NPbF

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	30	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	21	A
I <sub>DM</sub>	Pulsed Drain Current ①	120	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation	214	W
	Linear Derating Factor	1.4	W/°C
V <sub>GS</sub> Gate-to-Source Voltage		± 20	V
E <sub>AS</sub>			mJ
I <sub>AR</sub> Avalanche Current ①		30	A
E <sub>AR</sub>	Repetitive Avalanche Energy ①	21	mJ
dv/dt	Peak Diode Recovery dv/dt③	8.6	V/ns
Tj	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

### **Thermal Resistance**

Symbol	Parameter	Тур.	Max.	Units
$R_{ ext{ heta}JC}$	Junction-to-Case		0.7	
R <sub>ecs</sub>	Case-to-Sink, Flat, Greased Surface	0.24		°C/W
$R_{ heta JA}$	Junction-to-Ambient		40	







### Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	200			V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250µA
$\Delta V_{(BR)DSS} / \Delta T_J$	Breakdown Voltage Temp. Coefficient		0.26		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		_	0.075	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 18A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$
gfs	Forward Trans conductance	17			S	V <sub>DS</sub> = 50V, I <sub>D</sub> = 18A④
1	Drain-to-Source Leakage Current			25		V <sub>DS</sub> = 200V, V <sub>GS</sub> = 0V
IDSS				250	μΑ	V <sub>DS</sub> = 160V,V <sub>GS</sub> = 0V,T <sub>J</sub> =150°C
1	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 20V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	ПА	V <sub>GS</sub> = -20V

### Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	<b>Q</b> • • •		•	,	
Q <sub>g</sub>	Total Gate Charge	 	123		I <sub>D</sub> = 18A
Q <sub>gs</sub>	Gate-to-Source Charge	 	21	nC	V <sub>DS</sub> = 160V
$Q_{gd}$	Gate-to-Drain Charge		57		$V_{GS}$ = 10V, See Fig.6 and 13 $\oplus$
t <sub>d(on)</sub>	Turn-On Delay Time	 14			V <sub>DD</sub> = 100V
t <sub>r</sub>	Rise Time	 43		<b>n</b> 0	I <sub>D</sub> = 18A
t <sub>d(off)</sub>	Turn-Off Delay Time	 41		ns	R <sub>G</sub> = 3.9Ω
t <sub>f</sub>	Fall Time	 33			$R_{D}$ = 5.5 $\Omega$ , See Fig.10④
L <sub>D</sub>	Internal Drain Inductance	 5.0			Between lead, 6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance	 13			from package
C <sub>iss</sub>	Input Capacitance	 2159			V <sub>GS</sub> = 0V
C <sub>oss</sub>	Output Capacitance	 315		pF	V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance	 83			f = 1.0MHz, See Fig.5
Diode Ch	naracteristics				

### Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)			30		MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①			120		integral reverse and the p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	T <sub>J</sub> = 25°C,I <sub>S</sub> = 18A,V <sub>GS</sub> = 0V ④
t <sub>rr</sub>	Reverse Recovery Time		186	279	ns	T <sub>J</sub> = 25°C ,I <sub>F</sub> = 18A
Q <sub>rr</sub>	Reverse Recovery Charge		1.3	2.0	μC	di/dt = 100A/µs

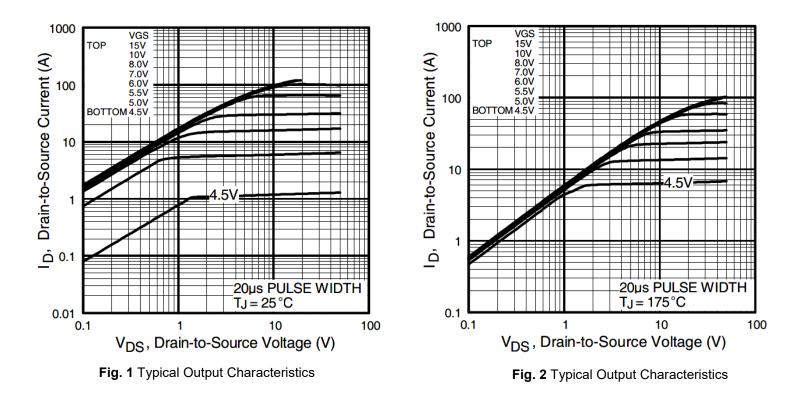
#### Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).

@ Starting T\_J = 25°C, L = 1.9mH, R\_G = 25\Omega, I\_{AS} = 18A.(See fig. 12).

④ Pulse width  $\leq$  300µs; duty cycle  $\leq$  2%.





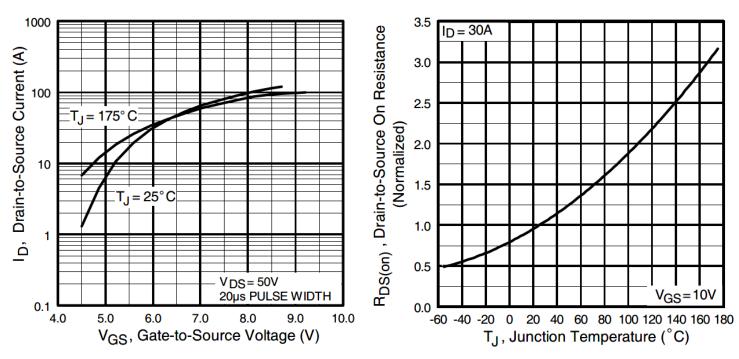
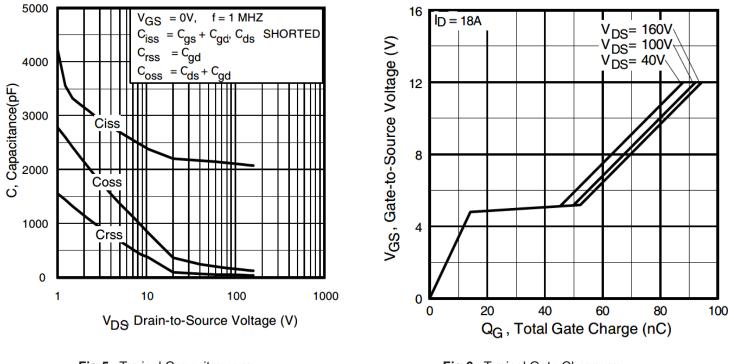


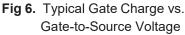
Fig. 3 Typical Transfer Characteristics

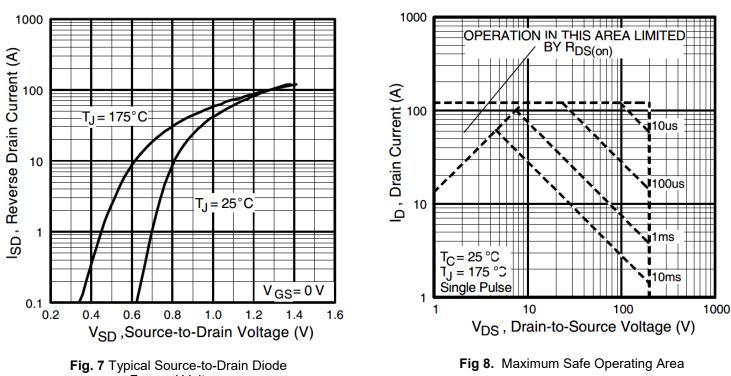
Fig. 4 Normalized On-Resistance vs. Temperature





**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage





Forward Voltage

## **IRFP250NPbF**



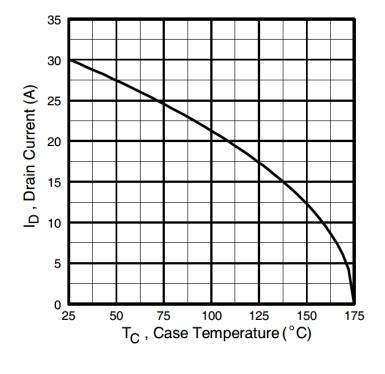


Fig 9. Maximum Drain Current vs. Case Temperature

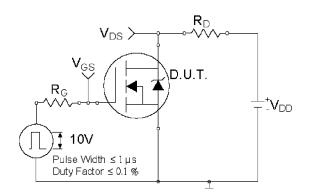


Fig 10a. Switching Time Test Circuit

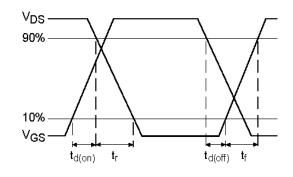
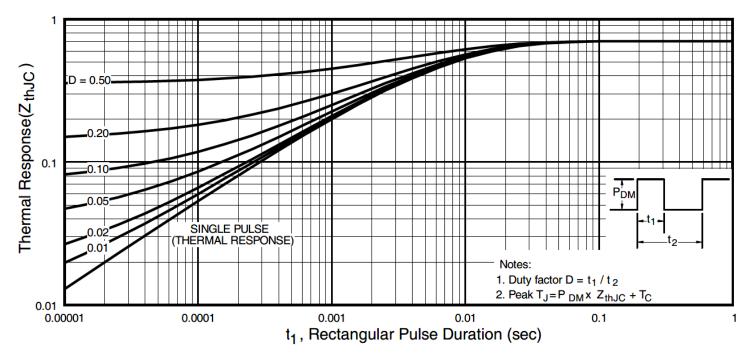


Fig 10a. Switching Time Waveforms



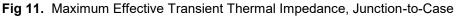




Fig. 12a. Unclamped Inductive Test Circuit

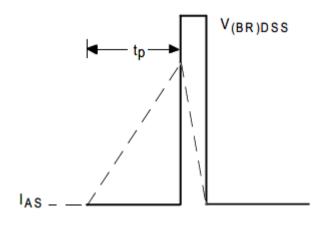


Fig. 12b. Unclamped Inductive Waveforms

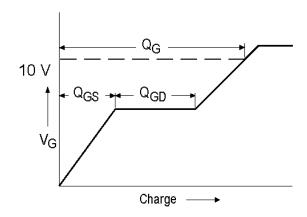


Fig 13a. Basic Gate Charge Waveform

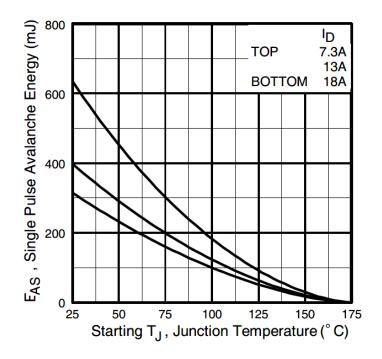


Fig 12c. Maximum Avalanche Energy vs. Drain Current

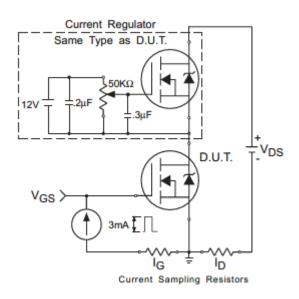
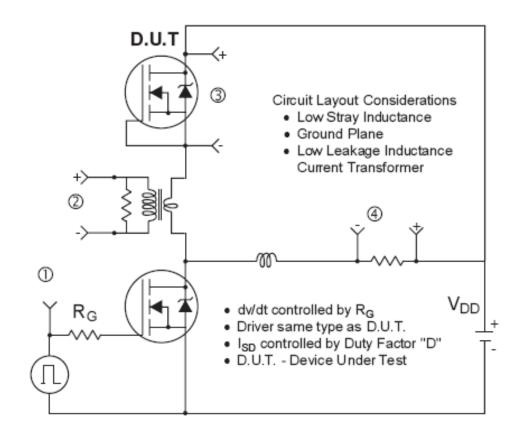
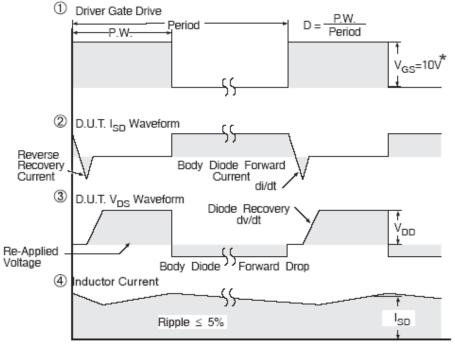


Fig 13b. Gate Charge Test Circuit



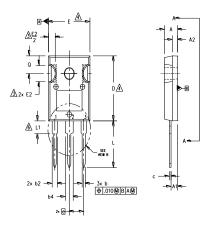




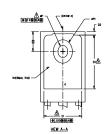
\*  $V_{GS}$  = 5V for Logic Level Devices

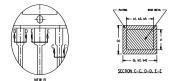
Fig 14. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

### TO-247AC Package Outline (Dimensions are









### **TO-247AC Part Marking Information**



- 1. DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M 1994.
- DIMENSIONS ARE SHOWN IN INCHES.
- 3 CONTOUR OF SLOT OPTIONAL.
- $\overline{\mathbb{A}}$ DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS D1 & E1.
- LEAD FINISH UNCONTROLLED IN L1.
- OP TO HAVE A MAXIMUM DRAFT ANGLE OF 1.5 ' TO THE TOP OF THE PART WITH A MAXIMUM HOLE DIAMETER OF .154 INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-247AC .

		DIMEN	ISIONS		
SYMBOL	INC	HES	MILLIN	IETERS	]
	MIN.	MAX.	MIN.	MAX.	NOTES
A	.183	.209	4.65	5.31	
A1	.087	.102	2.21	2.59	
A2	.059	.098	1.50	2.49	
b	.039	.055	0.99	1.40	
b1	.039	.053	0.99	1.35	
b2	.065	.094	1.65	2.39	
b3	.065	.092	1.65	2.34	
b4	.102	.135	2.59	3.43	
b5	.102	.133	2.59	3.38	
с	.015	.035	0.38	0.89	
c1	.015	.033	0.38	0.84	
D	.776	.815	19.71	20.70	4
D1	.515	-	13.08	-	5
D2	.020	.053	0.51	1.35	
Ε	.602	.625	15.29	15.87	4
E1	.530	-	13.46	-	
E2	.178	.216	4.52	5.49	
e	.215	BSC	5.46	BSC	
Øk	.0	10	0.	25	
L	.559	.634	14.20	16.10	
L1	.146	.169	3.71	4.29	
øР	.140	.144	3.56	3.66	
øP1	-	.291	-	7.39	
Q	.209	.224	5.31	5.69	
S	.217	BSC	5.51	BSC	

#### LEAD ASSIGNMENTS

infineon

<u>HEXFET</u>

1.- GATE 2.- DRAIN 3.- SOURCE 4.- DRAIN

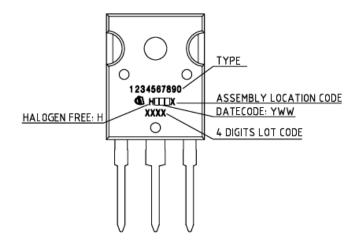
IGBTs, CoPACK

1.- GATE 2.- COLLECTOR 3.- EMITTER 4.- COLLECTOR

#### **DIODES**

1.- ANODE/OPEN 2.- CATHODE

3.- ANODE



TO-247AC package is not recommended for Surface Mount Application.

# IRFP250NPbF



### **Revision History**

Date	Rev.	Comments		
2024-10-08	2.1	<ul> <li>Update datasheet to Infineon format</li> <li>Updated Part marking –page 8</li> <li>Added disclaimer on last page.</li> </ul>		

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